

Total No. of Questions : 8]

SEAT No. :

P4834

[Total No. of Pages : 2

[5060] - 740

M.E. (E & TC) (VLSI & Embedded Systems)

SYSTEM ON CHIP DESIGN

(2013 Pattern) (Semester - II)

Time : 3 Hours]

[Max. Marks : 50

Instructions to the candidates :-

- 1) Answer any five questions.
- 2) Neat diagrams must be drawn wherever necessary.
- 3) Figures to the right indicator full marks.
- 4) Use of electronic pocket calculators is allowed.
- 5) Assume Suitable data if necessary.

Q1) a) Draw and explain hierarchy of abstraction levels. [4]

b) Differentiate Concurrency Vs parallelism. [4]

c) Explain the term deep-submicron effect. What is current CMOS design feature Size'? [2]

Q2) a) What are the limitations of 'data flow models'? In which model these are rectified? [4]

b) Explain with an example sequential targets for static schedule design.[4]

c) What is advantage of pipelining of SDF graphs'? [2]

Q3) a) Explain hardware implementation of Euclid's algorithm through SDF. [4]

b) Draw and explain CFG of the CGD program. [4]

c) Differentiate : CFD Vs DFG? [2]

Q4) a) What are limitations of FSMs? [4]

b) Draw and explain design flow to convert software source code into instructions for a processor. [4]

c) Why increased instruction latency of a RISC processor is usually not a problem? [2]

P.T.O.

- Q5)** a) When sequential read - write race occurs? Explain it with an example?[4]
b) Explain the scope of STA. What is its main limitation? [4]
c) Which factors affecting delay and slew? [2]
- Q6)** a) Explain the challenge with bus synchronization design? [4]
b) Explain the factors which affect power. [4]
c) How noise margin is maintained in 0.8 V domains using level shifter?[2]
- Q7)** a) Explain memory hierarchy trade-offs and characteristics. [4]
b) What are limitations of DRAM scheduler designs? [4]
c) Which techniques are used for lowering operating voltage? [2]
- Q8)** a) Explain energy - aware device scheduling algorithm. [4]
b) Explain SoC design flow for verification environment? [4]
c) Which IEEE standard is used for SoC test? Draw the IEEE SOC test architecture. [2]

